

Notice of References Cited	Application/Control No. 10/770,074		Applicant(s)/Patent Under Reexamination HAY, JENNIFER	
	Examiner Toan M. Le		Art Unit 2863	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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